

EAST - (10726881.wnp1)

File View Edit Tools Window Help

Drafts

BRS: 13 and

Pending

Active

L1: (5) ("3,733,587" or ("3,764,995")).PN.

L4: (9002) 324/765, 763, 760, 158.1.ccls.

L5: (35729) test\$4 near5 (IC! or integrated adj

L6: (2798) 4 and 5

L7: (11) 6 and ancillary

L8: (347) 6 and measur\$4 and analyz\$4

L9: (1135) 714/736, 734.ccls.

L10: (487) 9 and 5

L12: (200) 702/118.ccls.

L13: (83) 12 and 5

L14: (18) 13 and measur\$4 and analyz\$4

L11: (68) 10 and measur\$4 and analyz\$4

Failed

Saved

S1: (35729) test\$4 near5 (IC! or integrated adj

S2: (47) BOST and S1

Favorites

Tagged (3)

UDC

Queue

Trash

DB: US-PCPUB-USPAT-EPO-PO-DEVENT-IBM-TDB

Default operator: OR

10 and measur\$4 and analyz\$4

					Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	X	3	4	5	6	7	8
		Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	X	3	4	5	6	7	8
1	<input checked="" type="checkbox"/>	US 20040128601	20040701	24	Arrangements for self-measurement of I/O analysis module, integrated circuit sys.	714/734			Muljono, Harry et al.	<input checked="" type="checkbox"/>									
2	<input checked="" type="checkbox"/>	US 20040064772	20040401	11	System and method for testing circuitry on a	714/734			Weizman, Yoav et al.	<input checked="" type="checkbox"/>									
3	<input checked="" type="checkbox"/>	US 20030221152	20031127	31	Apparatus and method for testing fuses	714/736			Volkerink, Erik H. et al.	<input checked="" type="checkbox"/>									
4	<input checked="" type="checkbox"/>	US 6762608	20040713	15	Method and apparatus for dynamically testing	324/550	324/537;		Damon, Tim et al.	<input checked="" type="checkbox"/>									
5	<input checked="" type="checkbox"/>	US 6694464	20040217	61	B1	714/725	714/735;		Quayle, Barton L. et al.	<input checked="" type="checkbox"/>									
6	<input checked="" type="checkbox"/>	US 6690189	20040210	15	B2	324/765	324/158.1;		Mori, Hisaya et al.	<input checked="" type="checkbox"/>									
7	<input checked="" type="checkbox"/>	US 6617869	20030909	15	B1	324/763	324/533;		Pillkahn, Ulf	<input checked="" type="checkbox"/>									
8	<input checked="" type="checkbox"/>	US 6581172	20030617	12	B2	714/718	324/535;		Totorica, Robert L. et al.	<input checked="" type="checkbox"/>									
9	<input checked="" type="checkbox"/>	US 6578169	20030610	15	On-board testing circuit and method for	714/736	324/158.1;		Le, Anthony et al.	<input checked="" type="checkbox"/>									
					Data failure memory	714/736	714/30;												
					connection for communication		714/723												

HTTPS Details HTML

NUM

Ready